

# September 2010 UniFET-II TM

# FDP12N60NZ / FDPF12N60NZ N-Channel MOSFET

**600V**, **12A**, **0.65**Ω

### **Features**

- $R_{DS(on)} = 0.53\Omega$  ( Typ.)@  $V_{GS} = 10V$ ,  $I_D = 6A$
- Low gate charge (Typ. 26nC)
- Low C<sub>rss</sub> (Typ. 12pF)
- · Fast switching
- 100% avalanche tested
- · Improved dv/dt capability
- · ESD Improved capability
- · RoHS compliant

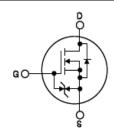
### **Description**

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DOMS technology.

This advance technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutationmode. These devices are well suited for high efficient switched mode power supplies and active power factor correction.







### MOSFET Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted\*

Symbol		Parameter		FDP12N60NZ	FDPF12N60NZ	Units
$V_{DSS}$	Drain to Source Voltage			60	V	
V <sub>GSS</sub>	Gate to Source Voltage			±	30	V
	Drain Current	-Continuous (T <sub>C</sub> = 25°C)		12	12*	Α
I <sub>D</sub>	Diam Current	-Continuous (T <sub>C</sub> = 100°C)		7.2	7.2*	A
I <sub>DM</sub>	Drain Current	1 3333			) 48 48*	
E <sub>AS</sub>	Single Pulsed Avalanche Energy		(Note 2)	565		mJ
I <sub>AR</sub>	Avalanche Current		(Note 1)	12		Α
E <sub>AR</sub>	Repetitive Avalanche Energy		(Note 1)	24		mJ
dv/dt	Peak Diode Recovery dv/dt		(Note 3)	10		V/ns
D	Bower Dissipation	$(T_C = 25^{\circ}C)$		240	39	W
$P_D$	Power Dissipation - Derate above 25°C			2.0	0.3	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range			-55 to +150		οС
T <sub>L</sub>	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds			30	00	°C

<sup>\*</sup>Drain current limited by maximum junction temperature

### **Thermal Characteristics**

Symbol	Parameter	FDP12N60NZ	FDPF12N60NZ	Units
$R_{\theta JC}$	Thermal Resistance, Junction to Case	0.52	3.2	
$R_{\theta CS}$	Thermal Resistance, Case to Sink Typ.	0.5	-	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	62.5	62.5	

## Package Marking and Ordering Information $T_C = 25^{\circ}C$ unless otherwise noted

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDP12N60NZ	FDP12N60NZ	TO-220	-	-	50
FDPF12N60NZ	FDPF12N60NZ	TO-220F	-	-	50

### **Electrical Characteristics**

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Units
Off Charac	cteristics					
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D = 250\mu A, V_{GS} = 0V, T_J = 25^{\circ} C$	600	-	-	V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250μA, Referenced to 25°C	-	0.6	-	V/°C
	Zero Gate Voltage Drain Current	$V_{DS} = 600V, V_{GS} = 0V$	-	-	1	
IDSS	Zero Gate voltage Drain Current	$V_{DS} = 480V, T_{C} = 125^{\circ}C$	-	-	10	μΑ
I <sub>GSS</sub>	Gate to Body Leakage Current	$V_{GS} = \pm 30V, V_{DS} = 0V$	-	-	±10	μΑ

### **On Characteristics**

V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	3	-	5	V
R <sub>DS(on)</sub>	Static Drain to Source On Resistance	$V_{GS} = 10V, I_D = 6A$	•	0.53	0.65	Ω
9 <sub>FS</sub>	Forward Transconductance	$V_{DS} = 20V, I_D = 6A$ (Note 4)	-	13.5	-	S

### **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = 25V, V <sub>GS</sub> = 0V f = 1MHz		-	1260	1676	pF
C <sub>oss</sub>	Output Capacitance			-	150	200	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 = 1101112		-	12	18	pF
Q <sub>g(tot)</sub>	Total Gate Charge at 10V			-	26	34	nC
$Q_{gs}$	Gate to Source Gate Charge	$V_{DS} = 480V, I_{D} = 12A$		-	6	-	nC
Q <sub>gd</sub>	Gate to Drain "Miller" Charge	V <sub>GS</sub> = 10V	(Note 4, 5)	=	10	-	nC

### **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time			-	25	60	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{DD} = 300V, I_D = 12A$		-	50	110	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$R_G = 25\Omega$		-	80	170	ns
t <sub>f</sub>	Turn-Off Fall Time		(Note 4, 5)	-	60	130	ns

### **Drain-Source Diode Characteristics**

$I_S$	Maximum Continuous Drain to Source Diode Forward Current			=	-	12	Α
I <sub>SM</sub>	Maximum Pulsed Drain to Source Diode Forward Current			-	-	48	Α
$V_{SD}$	Drain to Source Diode Forward Voltage V <sub>GS</sub> = 0V, I <sub>SD</sub> = 12A		-	-	1.4	V	
t <sub>rr</sub>	Reverse Recovery Time	$V_{GS} = 0V, I_{SD} = 12A$		-	350	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge	$V_{GS} = 0V, I_{SD} = 12A$ $dI_F/dt = 100A/\mu s$	(Note 4)	-	2.2	-	μС

- **Notes:**1. Repetitive Rating: Pulse width limited by maximum junction temperature 2: L =7.85mH,  $I_{AS}$  = 12A,  $V_{DD}$  = 50V,  $R_{G}$  = 25 $\Omega$ , Starting  $T_{J}$  = 25°C 3:  $I_{SD}$  ≤ 12A, di/dt ≤ 200A/ $\mu$ s,  $V_{DD}$  ≤ BV $_{DSS}$ , Starting  $T_{J}$  = 25°C 4: Pulse Test: Pulse width ≤ 300 $\mu$ s, Duty Cycle ≤ 2% 5: Essentially Independent of Operating Temperature Typical Characteristics

### **Typical Performance Characteristics**

Figure 1. On-Region Characteristics

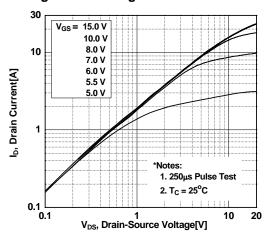


Figure 3. On-Resistance Variation vs.

Drain Current and Gate Voltage

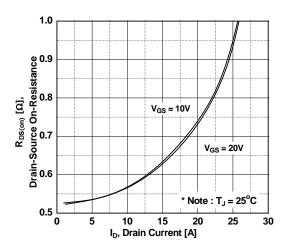


Figure 5. Capacitance Characteristics

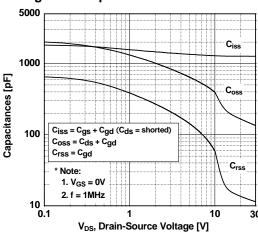


Figure 2. Transfer Characteristics

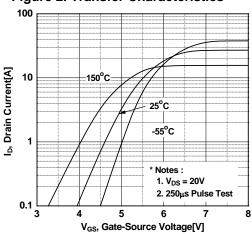


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

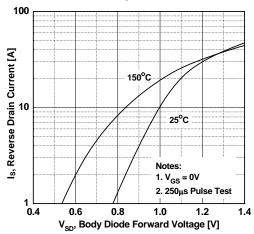
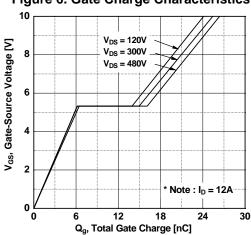


Figure 6. Gate Charge Characteristics



## **Typical Performance Characteristics** (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

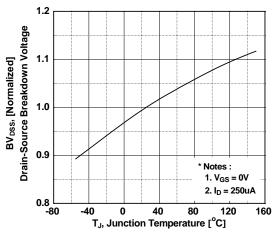


Figure 9. Maximum Safe Operating Area -FDPF12N60NZ

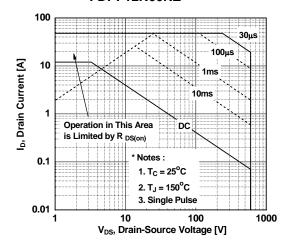


Figure 8. On-Resistance Variation vs Temperature

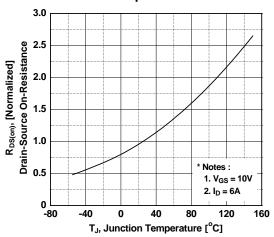


Figure 10. Maximum Safe Operating Area -FDP12N60NZ

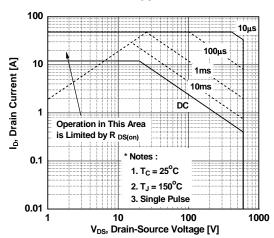


Figure 11. Maximum Drain Current vs Case Temperature

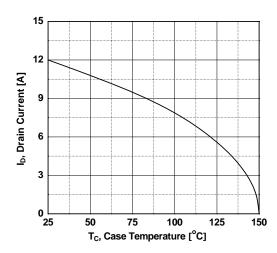


Figure 12. Transient Thermal Response Curve
-FDPF12N60NZ

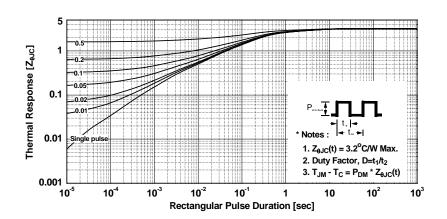
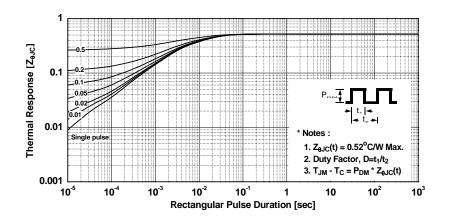
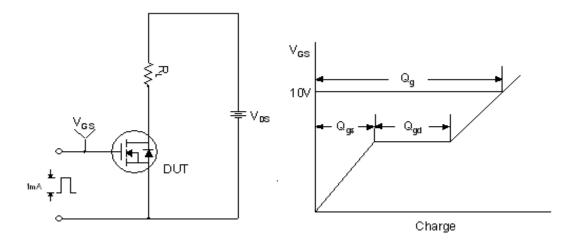


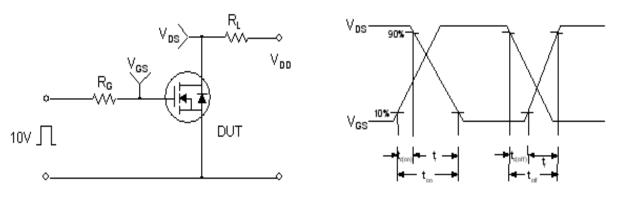
Figure 13. Transient Thermal Response Curve
-FDP12N60NZ



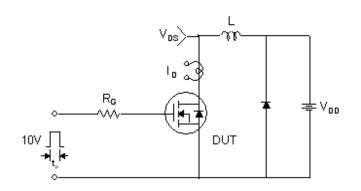
### **Gate Charge Test Circuit & Waveform**

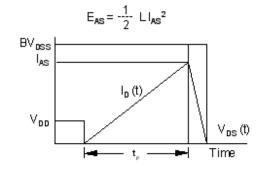


### **Resistive Switching Test Circuit & Waveforms**

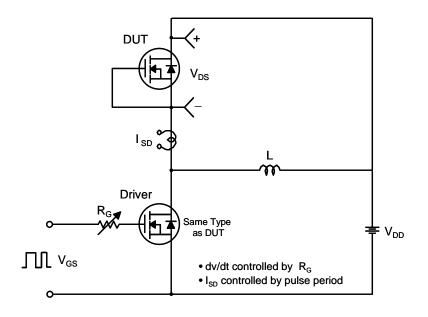


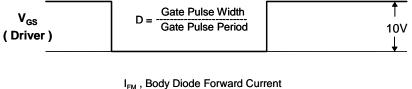
**Unclamped Inductive Switching Test Circuit & Waveforms** 

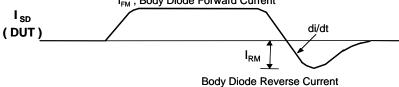


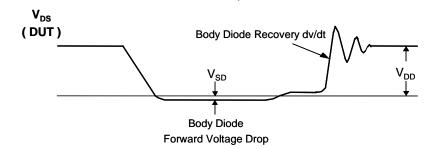


### Peak Diode Recovery dv/dt Test Circuit & Waveforms



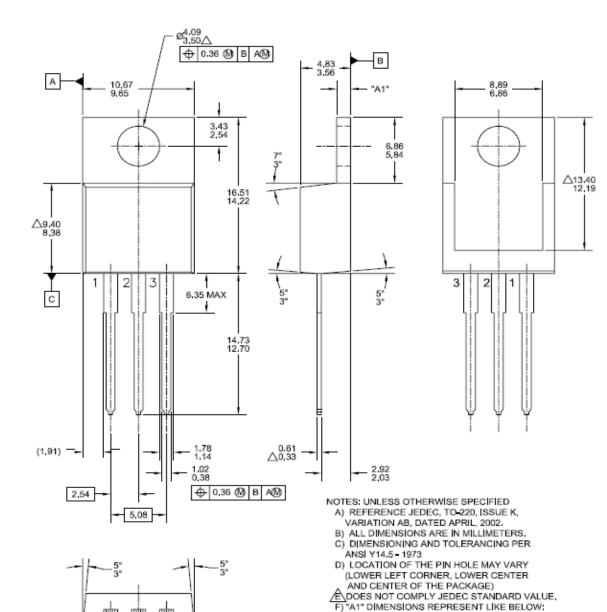






### **Mechanical Dimensions**

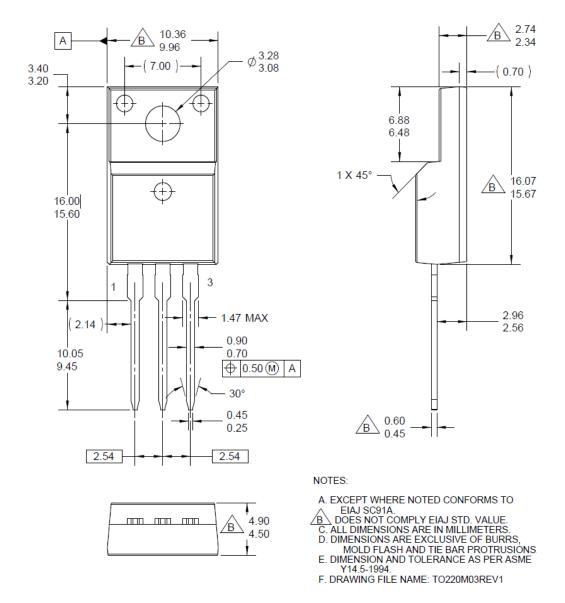
## TO-220



SINGLE GAUGE = 0.51 - 0.61 DUAL GAUGE = 1.14 - 1.40 G) DRAWING FILE NAME: TO220B03REV6

### Package Dimensions (Continued)

## TO-220F



\* Front/Back Side Isolation Voltage: 2500V

**Dimensions in Millimeters** 





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